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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

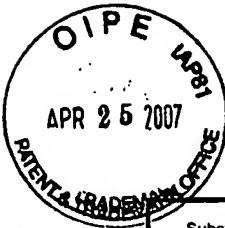
(Use as many sheets as necessary)

				Complete If Known	
				Application Number	10/774,682-Conf. #9428
				Filing Date	February 9, 2004
				First Named Inventor	Thomas RUECKES
				Art Unit	2823
				Examiner Name	W. D. Coleman
Sheet	1	of	5	Attorney Docket Number	0112020.00129US2(NAN-6)

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
/W.C./	AA*	US-2002/0130311-A1	09-19-2002	Lieber et al	
	AB*	US-2002/0136896-A1	09-26-2002	Takikawa et al.	
	AC*	US-2002/0172963-A1	11-21-2002	Kelley et al	
	AD*	US-2003/0021141	01-30-2003	Segal et al.	
	AE*	US-2003/0022428	01-30-2003	Segal et al.	
	AF*	US-2003/0042834-A1	03-06-2003	Dean et al.	
	AG*	US-2003/0091825-A1	05-15-2003	Shiffler et al.	
	AH*	US-2003/0118727-A1	06-26-2003	Ting et al.	
	AI*	US-2003/0122111-A1	07-03-2003	Glatkowski	
	AJ*	US-2003/0132823-A1	07-17-2003	Hyman et al.	
	AK*	US-2003/0177450-A1	09-18-2003	Nugent	
	AL*	US-2003/0180472-A1	09-25-2003	Zhou et al.	
	AM*	US-2003/0198812	10-23-2003	Rueckes et al.	
	AN*	US-2003/0200521-A1	10-23-2003	DeHon et al.	
	AO*	US-2003/0206436-A1	11-06-2003	Eaton et al.	
	AP*	US-2003/0234407-A1	12-25-2003	Vogeli et al	
	AQ*	US-2003/0236000-A1	12-25-2003	Vogeli et al	
	AR*	US-2004/0007528-A1	01-15-2004	Bakajin et al.	
	AS*	US-2004/0023514-A1	02-05-2004	Moriya et al.	
	AT*	US-2004/0071949-A1	04-15-2004	Glatkowski et al.	
	AU*	US-2004/0075159-A1	04-22-2004	Vogeli	
	AV*	US-2004/0077107-A1	04-22-2004	Vogeli	
	AW*	US-2004/0087162-A1	05-06-2004	Vogeli	
	AX*	US-2004/0099438-A1	05-27-2004	Arthur et al.	
	AY*	US-2004/0164289-A1	08-26-2004	Rueckes et al.	
	AZ*	US-2004/0191978-A1	09-30-2004	Rueckes et al	
	AA1*	US-2004/0214366-A1	10-28-2004	Segal et al.	
	AB1*	US-2004/0214367-A1	10-28-2004	Segal et al.	
	AC1*	US-2004/0238907-A1	12-02-2004	Pinkerton et al.	
	AD1*	US-2004/0253167-A1	12-16-2004	Silva et al.	
	AE1*	US-2004/0265550-A1	12-30-2004	Glatkowski et al.	
	AF1*	US-2005/0007002-A1	01-13-2005	Golovchenko et al.	
	AG1*	US-2005/0035344	02-17-2005	Bertin et al.	
	AH1*	US-2005/0035367-A1	02-17-2005	Bertin et al.	
	AI1*	US-2005/0035786	02-17-2005	Bertin et al.	
	AJ1*	US-2005/0035787	02-17-2005	Bertin et al.	
	AK1*	US-2005/0036365-A1	02-17-2005	Bertin et al.	
	AL1*	US-2005/0037547	02-17-2005	Bertin et al.	
	AM1*	US-2005/0040874-A1	02-24-2005	Allison et al.	
	AN1*	US-2005/0041465	02-24-2005	Rueckes et al.	
	AO1*	US-2005/0041466	02-24-2005	Rueckes et al.	
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	AQ1*	US-2005/0052894	03-01-2005	Segal et al.	
	AR1*	US-2005/0053525	03-10-2005	Segal et al.	
/W.C./	AS1*	US-2005/0056825-A1	03-17-2005	Bertin et al.	

Examiner Signature	Date Considered	06/21/2007
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PTO/SB/08A/B (09-06)

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Sheet	2	of	5	Attorney Docket Number	0112020.00129US2(NAN-6)
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W.C./	AT1*	Complete If Known			
		Application Number	Filing Date	First Named Inventor	Art Unit
	AU1*	US-2005/0056866	03-17-2005	Bertin et al.	
	AU1*	US-2005/0056877	03-01-2005	Rueckes et al.	
	AV1*	US-2005/0058590-A1	03-17-2005	Sen et al.	
	AW1*	US-2005/0058797-A1	03-17-2005	Sen et al.	
	AX1*	US-2005/0058834-A1	03-17-2005	Rueckes et al.	
	AY1*	US-2005/0059176	03-17-2005	Rueckes et al.	
	AZ1*	US-2005/0059210	03-17-2005	Rueckes et al.	
	AA2*	US-2005/0062035-A1	03-24-2005	Bertin et al.	
	AB2*	US-2005/0062062-A1	03-24-2005	Bertin et al.	
	AC2*	US-2005/0062070	03-24-2005	Bertin et al.	
	AD2*	US-2005/0063210	03-24-2005	Segal et al.	
	AE2*	US-2005/0063244-A1	03-24-2005	Bertin et al.	
	AF2*	US-2005/0065741	03-24-2005	Segal et al.	
	AG2*	US-2005/0068128-A1	03-31-2005	Yip	
	AH2*	US-2005/0074926	04-07-2005	Bertin et al.	
	AI2*	US-2005/0095938-A1	05-05-2005	Rosenberger et al.	
	AJ2*	US-2005/0101112	05-12-2005	Rueckes et al.	
	AK2*	US-2005/0128788	06-16-2005	Segal et al.	
	AL2*	US-2005/0174842	08-11-2005	Bertin et al.	
	AM2*	US-2005/0191495	09-01-2005	Rueckes et al.	
	AN2*	US-2005/0237781	10-27-2005	Bertin et al.	
	AO2*	US-2005/0269553	12-08-2005	Sen et al.	
	AP2*	US-2005/0269554	12-08-2005	Sen et al.	
	AQ2*	US-2005/0270824	12-08-2005	Bertin et al.	
	AR2*	US-2005/0279988	12-22-2005	Bertin	
	AS2*	US-2005/0280436	12-22-2005	Bertin	
	AT2*	US-2005/0281084	12-22-2005	Rueckes et al.	
	AU2*	US-2005/0282515	12-22-2005	Bertin	
	AV2*	US-2005/0282516	12-22-2005	Bertin	
	AW2*	US-2006/0044035	03-02-2006	Bertin	
	AX2*	US-2006/0052509-A1	03-09-2006	Saitoh	
	AY2*	US-2006/0061389	03-23-2006	Bertin	
	AZ2*	US-2006/0125033	06-15-2006	Segal et al.	
	AA3*	US-2006/0128049	06-15-2006	Jaiprakash et al.	
	AB3*	US-2006/0183278	08-17-2006	Bertin et al.	
	AC3*	US-2006/0193093	08-31-2006	Bertin et al.	
	AD3*	US-2006/0204427	09-14-2006	Ghenciu et al.	
	AE3*	US-2006/0231865	10-19-2006	Rueckes et al.	
	AF3*	US-2006/0237805	10-26-2006	Segal et al.	
	AG3*	US-2006/0237857-A1	10-26-2006	Bertin et al.	
	AH3*	US-2006/0250843	11-09-2006	Bertin et al.	
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	AK3*	US-2006/0276056	12-07-2006	Ward et al.	
	AL3*	US-2007/0015303	01-18-2007	Bertin et al.	
	AM3*	US-5,591,312	01-07-1997	Richard E. Smalley	
	AN3*	US-5,676,865	10-14-1997	Chang	
	W.C./	AC3*	US-5,721,862	02-24-1998	Sartore et al.

Examiner Signature		Date Considered	06/21/2007
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				<i>Complete If Known</i>
				Application Number 10/774,682-Conf. #9428
				Filing Date February 9, 2004
				First Named Inventor Thomas RUECKES
				Art Unit 2823
				Examiner Name W. D. Coleman
Sheet	3	of	5	Attorney Docket Number 0112020.00129US2(NAN-6)

W.C./	AP3*	US-5,829,125	11-03-1998	Fujimoto et al.
	AQ3*	US-6,057,637	05-02-2000	Zettl et al.
	AR3*	US-6,136,160	10-24-2000	Hrkut et al.
	AS3*	US-6,256,767	07-03-2001	Kuekes et al.
	AT3*	US-6,265,333-B1	07-24-2001	Dzenis et al.
	AU3*	US-6,340,822	01-22-2002	Brown et al.
	AV3*	US-6,342,276	01-29-2002	You et al.
	AW3*	US-6,376,787	04-23-2002	Martin et al.
	AX3*	US-6,394,158	05-28-2002	Momeni et al.
	AY3*	US-6,409,567	06-25-2002	Amey et al.
	AZ3*	US-6,426,687	07-30-2002	Osborn
	AA4*	US-6,440,761	08-27-2002	Choi et al.
	AB4*	US-6,528,020	03-04-2003	Dai et al.
	AC4*	US-6,533,620	03-18-2003	Franzen et al.
	AD4*	US-6,548,841-A1	04-15-2003	Frazier et al
	AE4*	US-6,559,468	05-06-2003	Kuekes et al
	AF4*	US-6,595,405	07-22-2003	Terunuma et al.
	AG4*	US-6,625,047-A1	09-23-2003	Coleman, Jr.
	AH4*	US-6,630,772	10-07-2003	Bower et al.
	AI4*	US-6,642,639-A1	11-04-2003	Choi et al.
	AJ4*	US-6,645,628-A1	11-11-2003	Shiffler, Jr. et al.
	AK4*	US-6,658,634	12-02-2003	Goodnow et al.
	AL4*	US-6,673,424	01-06-2004	Lindsay et al
	AM4*	US-6,705,152-A1	03-16-2004	Routkevitch et al.
	AN4*	US-6,707,098	03-16-2004	Hofmann et al.
	AO4*	US-6,709,566-A1	03-23-2004	Cumings et al.
	AP4*	US-6,743,408-A1	06-01-2004	Lieber et al.
	AQ4*	US-6,750,471	06-15-2004	Bethune et al
	AR4*	US-6,759,693	07-06-2004	Vogeli et al
	AS4*	US-6,774,052	08-10-2004	Vogeli et al
	AT4*	US-6,781,166	08-24-2004	Lieber et al
	AU4*	US-6,803,840-A1	10-12-2004	Hunt et al
	AV4*	US-6,808,746	10-26-2004	Dai et al.
	AW4*	US-6,809,462	10-26-2004	Pelrine et al.
	AX4*	US-6,809,465-A1	10-26-2004	Jin
	AY4*	US-6,833,558-A1	12-21-2004	Lee et al.
	AZ4*	US-6,835,591	12-28-2004	Rueckes et al
	AA5*	US-6,858,197	02-22-2005	Delzeit
	AB5*	US-6,863,942-A1	03-08-2005	Ren et al.
	AC5*	US-6,896,864-A1	05-24-2005	Clarke
	AD5*	US-6,911,682-A1	06-28-2005	Rueckes et al.
	AE5*	US-6,918,284-B2	07-19-2005	Snow et al.
	AF5*	US-6,919,529	07-19-2005	Franzen et al.
	AG5*	US-6,919,740-A1	07-19-2005	Snider
	AH5*	US-6,921,575-A1	07-26-2005	Horiuchi et al.
	AI5*	US-6,924,538-A1	08-02-2005	Jaiprakash et al.
	AJ5*	US-6,946,410	09-20-2005	French et al.
	AK5*	US-6,955,937	10-18-2005	Burke et al.

Examiner Signature		Date Considered	06/21/2007
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Substitute for form 1449/PTO				Complete If Known	
				Application Number	10/774,682-Conf. #9428
				Filing Date	February 9, 2004
				First Named Inventor	Thomas RUECKES
				Art Unit	2823
				Examiner Name	W. D. Coleman
Sheet	4	of	5	Attorney Docket Number	
0112020.00129US2(NAN-6)					

W.C./	ALS*	US-6,969,651	11-29-2005	Lu et al.	
W.C./	AM5*	US-7,015,500-A1	03-21-2006	Choi et al.	
W.C./	AN5*	US-7,048,999-A1	05-23-2006	Smalley et al.	

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Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ²
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
W.C./	BA	DE-19504967	08/22/1996	Fraunhofer Ges Forschung		
W.C./	BB	DE-19644121	05/07/1997	Hewlett Packard Co		✓
W.C./	BC	DE-19929179	01/11/2001	Siemens Ag		
W.C./	BD	DE-4446289	06/27/1996	Finn David et al.		
W.C./	BE	EP-1186370	03/13/2002	Siemens Ag		
W.C./	BF	JP-1146426	06/08/1989	Mitsubishi Electric Corp		
W.C./	BG	JP-2001-035362	02/09/2001	Futaba Corp.		
W.C./	BH	JP-2004-090208	03/24/2004	Fuji Xerox Co. Ltd.		
W.C./	BI	WO-00/9841	08/24/2000	Siemens Ag et al.		
W.C./	BJ	WO-03/091486	11/06/2003	Nantero Inc		
W.C./	BK	WO-04/039893	05/13/2004	Mitsubishi Rayon		
W.C./	BL	WO-04/065655	08/05/2004	Nantero, Inc.		
W.C./	BM	WO-04/065657	08/05/2004	Nantero, Inc.		
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W.C./	BO	WO-98/44593	10/08/1998	Siemens Ag et al.		

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
W.C./	CA	BRADLEY, K. et al., "Flexible Nanotube Electronics," <i>Nano Letters</i> , Vol. 3, No. 10, pp. 1353-1355, 2003			
W.C./	CB	CASAVANT, M.J. et al, "Neat macroscopic membranes of aligned carbon nanotubes," <i>Journal of Appl. Phys.</i> , 15 February 2003, Vol. 93, No. 4, pp. 2153-2156			
W.C./	CC	CHOI, W.B. et al, "Carbon-nanotube-based nonvolatile memory with oxide-nitride-oxide film and nanoscale channel," <i>Appl. Phys. Lett.</i> , 13 January 2003, Vol. 82, No. 2, pp. 275-277			
W.C./	CD	CUI, J.B. et al, "Carbon Nanotube Memory Devices of High Charge Storage Stability," <i>Appl. Phys. Lett.</i> , 21 October 2002, Vol. 81, No. 17, pp. 3260-3262			
W.C./	CE	DEQUESNES, M. et al, "Simulation of carbon nanotube-based nanoelectromechanical switches," <i>Computational Nanoscience and Nanotechnology</i> , 2002, pp. 383-386			
W.C./	CF	DESAI et al., "Freestanding Carbon Nanotube Specific Fabrication," Proc. of 2005 5th IEEE Conf., Nanotech., Nagoya, Japan, pp. 1-4, July 2005			
W.C./	CG	FARAJIAN, A. A. et al, "Electronic transport through bent carbon nanotubes: Nanoelectromechanical sensors and switches," <i>Phys. Rev. B</i> , 2003, Vol. 67, pp. 205423-1 - 205423-6			

Examiner Signature	Date Considered	06/21/2007
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>				Application Number	10/774,682-Conf. #9428
Sheet	5	of	5	Filing Date	February 9, 2004
				First Named Inventor	Thomas RUECKES
				Art Unit	2823
				Examiner Name	W. D. Coleman
				Attorney Docket Number	0112020.00129US2(NAN-6)

CH	FISCHER, J.E. et al, "Magnetically aligned single wall carbon nanotube films: Preferred orientation and anisotropic transport properties," <i>Journal of Appl. Phys.</i> , 15 February 2003, Vol. 93, No. 4, pp. 2157-2163	
CI	KANETO, K. et al., "Electrical conductivities of multi-wall carbon nano tubes," <i>Synthetic Metals</i> , Elsevier Science S.A. (1999), Vol. 103, pp. 2543-2546	
CJ	KINARET, J. M. et al., "A carbon-nanotube-based nanorelay," <i>Applied Physics Letters</i> , 24 February 2003, Vol. 82, No. 8, pp. 1287-1289	
CK	LEE, K.H. et al, "Control of growth orientation for carbon nanotubes," <i>Appl. Phys. Lett.</i> , 20 January 2003, Vol. 82, No. 3, pp. 448-450	
CL	MARTEL, R., et al. "Carbon Nanotube Field-Effect Transistors and Logic Circuits," <i>DAC 2002</i> , 10-12 June 2002, Vol. 7.4, pp. 94-98	
CM	ONOA, G.B., et al., "Bulk production of singly dispersed carbon nanotubes with prescribed lengths," <i>Nanotechnology</i> , Vol. 16, pp. 2799-2803, 2005	
CN	SREEKUMAR, T.V. et al, "Single-wall Carbon Nanotube Films," <i>Chem. Mater.</i> , 2003, Vol. 15, pp. 175-178	
CO	STADERMANN, M. et al., "Nanoscale study of conduction through carbon nanotube networks," <i>Phys. Rev. B</i> 69, 201402(R), 2004	
CP	TENNE, Richard and Alex K. Zettl. "Nanotubes from inorganic Materials," <i>Topics in Applied Physics</i> (2001); 80, 81-112	
CQ	TOUR, J.M. et al, "NanoCell Electronic Memories," <i>J. Am. Chem. Soc.</i> , 2003, Vol. 125, pp. 13279-13283	
CR	VERISSIMO-ALVES, M. et al, "Electromechanical effects in carbon nanotubes: <i>Ab initio</i> and analytical tight-binding calculations," <i>Phys. Rev. B</i> , 2003, Vol. 67, pp. 161401-1 - 161401-4	
CS	YAO, B. D. and N. Wang. "Carbon Nanotube Arrays Prepared by MWCVD," <i>Journal of Physical Chemistry</i> (2001); 105, 11395-11398	
CT	ZHAN, W. et al, "Microelectrochemical Logic Circuits," <i>J. Am. Chem. Soc.</i> , 2003, Vol. 125, pp. 9934-9935	
CU	ZHAO, Y.-P. et al. "Frequency-dependent electrical transport in carbon nanotubes," <i>Physical Review B</i> (2001); 64, 201402(4)	

¹EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ²CITE NO.: Those application(s) which are marked with an single asterisk (*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. ³Applicant's unique citation designation number (optional). ⁴See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ⁵Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁶For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁷Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁸Applicant is to place a check mark here if English language Translation is attached.

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Substitute for form 1449A/B/PTO				<i>Complete If Known</i>	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Application Number	10/774682-Conf. #9428
<i>(Use as many sheets as necessary)</i>				Filing Date	February 9, 2004
				First Named Inventor	Brent M. Segal
				Art Unit	2823
				Examiner Name	W. D. Coleman
Sheet	1	of	1	Attorney Docket Number	
0112020.00129US2					

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (If known)			

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code ³ -Number ⁴ -Kind Code ⁵ (If known)			
/W.C./	BA	JP2002170480	06-14-2002	NEC Corp.	T ⁶

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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume/issue number(s), publisher, city and/or country where published.			
/W.C./	CA	Calleja, M., "Fabrication of gold nanowires on insulating substrates by field-induced mass transport." Applied Physics Letters, October 8, 2001, Vol. 79, pp. 2471-2473			
/W.C./	CB	Sax, Herald, "Polysilicon Overfill Etch Back Using Wet Chemical Spin-process Technology," (7 pages)			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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